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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	1395
Number of Logic Elements/Cells	22320
Total RAM Bits	608256
Number of I/O	153
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 125°C (TJ)
Package / Case	256-LBGA
Supplier Device Package	256-FBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep4ce22f17a7n


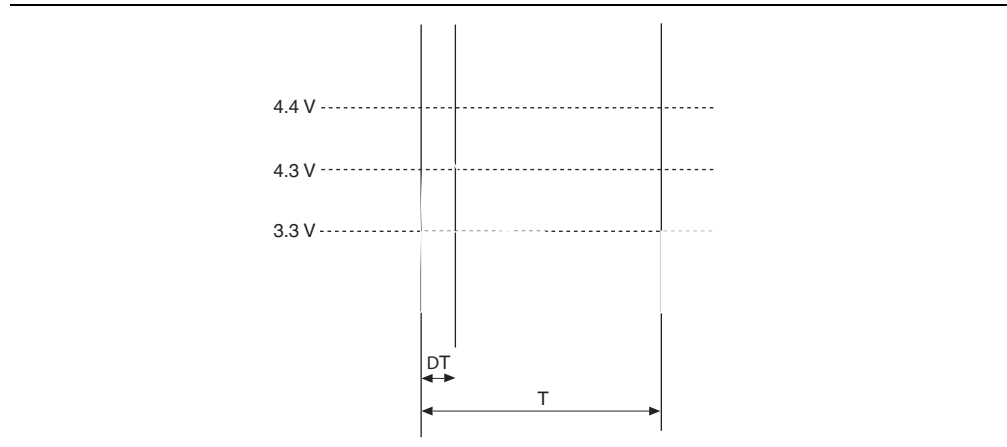
 A DC signal is equivalent to 100% duty cycle. For example, a signal that overshoots to 4.3 V can only be at 4.3 V for 65% over the lifetime of the device; for a device lifetime of 10 years, this amounts to 65/10ths of a year.

Table 1–2. Maximum Allowed Overshoot During Transitions over a 10-Year Time Frame for Cyclone IV Devices

Symbol	Parameter	Condition (V)	Overshoot Duration as % of High Time	Unit
V_i	AC Input Voltage	$V_i = 4.20$	100	%
		$V_i = 4.25$	98	%
		$V_i = 4.30$	65	%
		$V_i = 4.35$	43	%
		$V_i = 4.40$	29	%
		$V_i = 4.45$	20	%
		$V_i = 4.50$	13	%
		$V_i = 4.55$	9	%
		$V_i = 4.60$	6	%

Figure 1–1 shows the methodology to determine the overshoot duration. The overshoot voltage is shown in red and is present on the input pin of the Cyclone IV device at over 4.3 V but below 4.4 V. From Table 1–2, for an overshoot of 4.3 V, the percentage of high time for the overshoot can be as high as 65% over a 10-year period. Percentage of high time is calculated as $([\Delta T]/T) \times 100$. This 10-year period assumes that the device is always turned on with 100% I/O toggle rate and 50% duty cycle signal. For lower I/O toggle rates and situations in which the device is in an idle state, lifetimes are increased.

Figure 1–1. Cyclone IV Devices Overshoot Duration



Recommended Operating Conditions

This section lists the functional operation limits for AC and DC parameters for Cyclone IV devices. Table 1–3 and Table 1–4 list the steady-state voltage and current values expected from Cyclone IV E and Cyclone IV GX devices. All supplies must be strictly monotonic without plateaus.

Table 1–3. Recommended Operating Conditions for Cyclone IV E Devices ⁽¹⁾, ⁽²⁾ (Part 1 of 2)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{CCINT}^{(3)}$	Supply voltage for internal logic, 1.2-V operation	—	1.15	1.2	1.25	V
	Supply voltage for internal logic, 1.0-V operation	—	0.97	1.0	1.03	V
$V_{CCIO}^{(3), (4)}$	Supply voltage for output buffers, 3.3-V operation	—	3.135	3.3	3.465	V
	Supply voltage for output buffers, 3.0-V operation	—	2.85	3	3.15	V
	Supply voltage for output buffers, 2.5-V operation	—	2.375	2.5	2.625	V
	Supply voltage for output buffers, 1.8-V operation	—	1.71	1.8	1.89	V
	Supply voltage for output buffers, 1.5-V operation	—	1.425	1.5	1.575	V
	Supply voltage for output buffers, 1.2-V operation	—	1.14	1.2	1.26	V
$V_{CCA}^{(3)}$	Supply (analog) voltage for PLL regulator	—	2.375	2.5	2.625	V
$V_{CCD_PLL}^{(3)}$	Supply (digital) voltage for PLL, 1.2-V operation	—	1.15	1.2	1.25	V
	Supply (digital) voltage for PLL, 1.0-V operation	—	0.97	1.0	1.03	V
V_I	Input voltage	—	–0.5	—	3.6	V
V_O	Output voltage	—	0	—	V_{CCIO}	V
T_J	Operating junction temperature	For commercial use	0	—	85	°C
		For industrial use	–40	—	100	°C
		For extended temperature	–40	—	125	°C
		For automotive use	–40	—	125	°C
t_{RAMP}	Power supply ramp time	Standard power-on reset (POR) ⁽⁵⁾	50 μ s	—	50 ms	—
		Fast POR ⁽⁶⁾	50 μ s	—	3 ms	—

Table 1-4. Recommended Operating Conditions for Cyclone IV GX Devices (Part 2 of 2)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{CCA_GXB}	Transceiver PMA and auxiliary power supply	—	2.375	2.5	2.625	V
V_{CCL_GXB}	Transceiver PMA and auxiliary power supply	—	1.16	1.2	1.24	V
V_I	DC input voltage	—	-0.5	—	3.6	V
V_O	DC output voltage	—	0	—	V_{CCIO}	V
T_J	Operating junction temperature	For commercial use	0	—	85	°C
		For industrial use	-40	—	100	°C
t_{RAMP}	Power supply ramp time	Standard power-on reset (POR) ⁽⁷⁾	50 μ s	—	50 ms	—
		Fast POR ⁽⁸⁾	50 μ s	—	3 ms	—
I_{Diode}	Magnitude of DC current across PCI-clamp diode when enabled	—	—	—	10	mA

Notes to Table 1-4:

- (1) All V_{CCA} pins must be powered to 2.5 V (even when PLLs are not used) and must be powered up and powered down at the same time.
- (2) You must connect V_{CCD_PLL} to V_{CCINT} through a decoupling capacitor and ferrite bead.
- (3) Power supplies must rise monotonically.
- (4) V_{CCIO} for all I/O banks must be powered up during device operation. Configurations pins are powered up by V_{CCIO} of I/O Banks 3, 8, and 9 where I/O Banks 3 and 9 only support V_{CCIO} of 1.5, 1.8, 2.5, 3.0, and 3.3 V. For fast passive parallel (FPP) configuration mode, the V_{CCIO} level of I/O Bank 8 must be powered up to 1.5, 1.8, 2.5, 3.0, and 3.3 V.
- (5) You must set V_{CC_CLKIN} to 2.5 V if you use $CLKIN$ as a high-speed serial interface (HSSI) $refclk$ or as a $DIFFCLK$ input.
- (6) The $CLKIN$ pins in I/O Banks 3B and 8B can support single-ended I/O standard when the pins are used to clock left PLLs in non-transceiver applications.
- (7) The POR time for Standard POR ranges between 50 and 200 ms. V_{CCINT} , V_{CCA} , and V_{CCIO} of I/O Banks 3, 8, and 9 must reach the recommended operating range within 50 ms.
- (8) The POR time for Fast POR ranges between 3 and 9 ms. V_{CCINT} , V_{CCA} , and V_{CCIO} of I/O Banks 3, 8, and 9 must reach the recommended operating range within 3 ms.

ESD Performance

This section lists the electrostatic discharge (ESD) voltages using the human body model (HBM) and charged device model (CDM) for Cyclone IV devices general purpose I/Os (GPIOs) and high-speed serial interface (HSSI) I/Os. Table 1-5 lists the ESD for Cyclone IV devices GPIOs and HSSI I/Os.

Table 1-5. ESD for Cyclone IV Devices GPIOs and HSSI I/Os

Symbol	Parameter	Passing Voltage	Unit
V_{ESDHBM}	ESD voltage using the HBM (GPIOs) ⁽¹⁾	± 2000	V
	ESD using the HBM (HSSI I/Os) ⁽²⁾	± 1000	V
V_{ESDCDM}	ESD using the CDM (GPIOs)	± 500	V
	ESD using the CDM (HSSI I/Os) ⁽²⁾	± 250	V

Notes to Table 1-5:

- (1) The passing voltage for EP4CGX15 and EP4CGX30 row I/Os is ± 1000 V.
- (2) This value is applicable only to Cyclone IV GX devices.

Table 1–7. Bus Hold Parameter for Cyclone IV Devices (Part 2 of 2) ⁽¹⁾

Parameter	Condition	V _{CCIO} (V)												Unit
		1.2		1.5		1.8		2.5		3.0		3.3		
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Bus hold trip point	—	0.3	0.9	0.375	1.125	0.68	1.07	0.7	1.7	0.8	2	0.8	2	V

Note to Table 1–7:

(1) Bus hold trip points are based on the calculated input voltages from the JEDEC standard.

OCT Specifications

Table 1–8 lists the variation of OCT without calibration across process, temperature, and voltage (PVT).

Table 1–8. Series OCT Without Calibration Specifications for Cyclone IV Devices

Description	V_{CCIO} (V)	Resistance Tolerance		Unit
		Commercial Maximum	Industrial, Extended industrial, and Automotive Maximum	
Series OCT without calibration	3.0	±30	±40	%
	2.5	±30	±40	%
	1.8	±40	±50	%
	1.5	±50	±50	%
	1.2	±50	±50	%

OCT calibration is automatically performed at device power-up for OCT-enabled I/Os.

Table 1–9 lists the OCT calibration accuracy at device power-up.

Table 1–9. Series OCT with Calibration at Device Power-Up Specifications for Cyclone IV Devices

Description	V_{CCIO} (V)	Calibration Accuracy		Unit
		Commercial Maximum	Industrial, Extended industrial, and Automotive Maximum	
Series OCT with calibration at device power-up	3.0	±10	±10	%
	2.5	±10	±10	%
	1.8	±10	±10	%
	1.5	±10	±10	%
	1.2	±10	±10	%

Example 1–1 shows how to calculate the change of 50-Ω I/O impedance from 25°C at 3.0 V to 85°C at 3.15 V.

Example 1–1. Impedance Change

$$\Delta R_V = (3.15 - 3) \times 1000 \times -0.026 = -3.83$$

$$\Delta R_T = (85 - 25) \times 0.262 = 15.72$$

Because ΔR_V is negative,

$$MF_V = 1 / (3.83/100 + 1) = 0.963$$

Because ΔR_T is positive,

$$MF_T = 15.72/100 + 1 = 1.157$$

$$MF = 0.963 \times 1.157 = 1.114$$

$$R_{\text{final}} = 50 \times 1.114 = 55.71 \, \Omega$$

Pin Capacitance

Table 1–11 lists the pin capacitance for Cyclone IV devices.

Table 1–11. Pin Capacitance for Cyclone IV Devices ⁽¹⁾

Symbol	Parameter	Typical – Quad Flat Pack (QFP)	Typical – Quad Flat No Leads (QFN)	Typical – Ball-Grid Array (BGA)	Unit
C _{IOTB}	Input capacitance on top and bottom I/O pins	7	7	6	pF
C _{IOLR}	Input capacitance on right I/O pins	7	7	5	pF
C _{LVDSLR}	Input capacitance on right I/O pins with dedicated LVDS output	8	8	7	pF
C _{VREFLR} (2)	Input capacitance on right dual-purpose V _{REF} pin when used as V _{REF} or user I/O pin	21	21	21	pF
C _{VREFTB} (2)	Input capacitance on top and bottom dual-purpose V _{REF} pin when used as V _{REF} or user I/O pin	23 (3)	23	23	pF
C _{CLKTB}	Input capacitance on top and bottom dedicated clock input pins	7	7	6	pF
C _{CLKLR}	Input capacitance on right dedicated clock input pins	6	6	5	pF

Notes to Table 1–11:

- (1) The pin capacitance applies to FBGA, UBGA, and MBGA packages.
- (2) When you use the V_{REF} pin as a regular input or output, you can expect a reduced performance of toggle rate and t_{CO} because of higher pin capacitance.
- (3) C_{VREFTB} for the EP4CE22 device is 30 pF.

Internal Weak Pull-Up and Weak Pull-Down Resistor

Table 1-12 lists the weak pull-up and pull-down resistor values for Cyclone IV devices.

Table 1-12. Internal Weak Pull-Up and Weak Pull-Down Resistor Values for Cyclone IV Devices ⁽¹⁾

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
R _{PU}	Value of the I/O pin pull-up resistor before and during configuration, as well as user mode if you enable the programmable pull-up resistor option	V _{CCIO} = 3.3 V ± 5% ^{(2), (3)}	7	25	41	kΩ
		V _{CCIO} = 3.0 V ± 5% ^{(2), (3)}	7	28	47	kΩ
		V _{CCIO} = 2.5 V ± 5% ^{(2), (3)}	8	35	61	kΩ
		V _{CCIO} = 1.8 V ± 5% ^{(2), (3)}	10	57	108	kΩ
		V _{CCIO} = 1.5 V ± 5% ^{(2), (3)}	13	82	163	kΩ
		V _{CCIO} = 1.2 V ± 5% ^{(2), (3)}	19	143	351	kΩ
R _{PD}	Value of the I/O pin pull-down resistor before and during configuration	V _{CCIO} = 3.3 V ± 5% ⁽⁴⁾	6	19	30	kΩ
		V _{CCIO} = 3.0 V ± 5% ⁽⁴⁾	6	22	36	kΩ
		V _{CCIO} = 2.5 V ± 5% ⁽⁴⁾	6	25	43	kΩ
		V _{CCIO} = 1.8 V ± 5% ⁽⁴⁾	7	35	71	kΩ
		V _{CCIO} = 1.5 V ± 5% ⁽⁴⁾	8	50	112	kΩ

Notes to Table 1-12:

- (1) All I/O pins have an option to enable weak pull-up except the configuration, test, and JTAG pins. The weak pull-down feature is only available for JTAG TCK.
- (2) Pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO}.
- (3) $R_{PU} = (V_{CCIO} - V_I) / I_{R_{PU}}$
Minimum condition: -40°C; V_{CCIO} = V_{CC} + 5%, V_I = V_{CC} + 5% - 50 mV;
Typical condition: 25°C; V_{CCIO} = V_{CC}, V_I = 0 V;
Maximum condition: 100°C; V_{CCIO} = V_{CC} - 5%, V_I = 0 V; in which V_I refers to the input voltage at the I/O pin.
- (4) $R_{PD} = V_I / I_{R_{PD}}$
Minimum condition: -40°C; V_{CCIO} = V_{CC} + 5%, V_I = 50 mV;
Typical condition: 25°C; V_{CCIO} = V_{CC}, V_I = V_{CC} - 5%;
Maximum condition: 100°C; V_{CCIO} = V_{CC} - 5%, V_I = V_{CC} - 5%; in which V_I refers to the input voltage at the I/O pin.

Hot-Socketing

Table 1-13 lists the hot-socketing specifications for Cyclone IV devices.

Table 1-13. Hot-Socketing Specifications for Cyclone IV Devices

Symbol	Parameter	Maximum
I _{IOPIN(DC)}	DC current per I/O pin	300 μA
I _{IOPIN(AC)}	AC current per I/O pin	8 mA ⁽¹⁾
I _{XCVRTX(DC)}	DC current per transceiver TX pin	100 mA
I _{XCVRRX(DC)}	DC current per transceiver RX pin	50 mA

Note to Table 1-13:

- (1) The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns, |I_{IOPIN}| = C dv/dt, in which C is the I/O pin capacitance and dv/dt is the slew rate.



During hot-socketing, the I/O pin capacitance is less than 15 pF and the clock pin capacitance is less than 20 pF.

Table 1-16. Single-Ended SSTL and HSTL I/O Reference Voltage Specifications for Cyclone IV Devices ⁽¹⁾

I/O Standard	V _{CCIO} (V)			V _{REF} (V)			V _{TT} (V) ⁽²⁾		
	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max
SSTL-2 Class I, II	2.375	2.5	2.625	1.19	1.25	1.31	V _{REF} - 0.04	V _{REF}	V _{REF} + 0.04
SSTL-18 Class I, II	1.7	1.8	1.9	0.833	0.9	0.969	V _{REF} - 0.04	V _{REF}	V _{REF} + 0.04
HSTL-18 Class I, II	1.71	1.8	1.89	0.85	0.9	0.95	0.85	0.9	0.95
HSTL-15 Class I, II	1.425	1.5	1.575	0.71	0.75	0.79	0.71	0.75	0.79
HSTL-12 Class I, II	1.14	1.2	1.26	0.48 × V _{CCIO} ⁽³⁾	0.5 × V _{CCIO} ⁽³⁾	0.52 × V _{CCIO} ⁽³⁾	—	0.5 × V _{CCIO}	—
				0.47 × V _{CCIO} ⁽⁴⁾	0.5 × V _{CCIO} ⁽⁴⁾	0.53 × V _{CCIO} ⁽⁴⁾			

Notes to Table 1-16:

- (1) For an explanation of terms used in Table 1-16, refer to “Glossary” on page 1-37.
- (2) V_{TT} of the transmitting device must track V_{REF} of the receiving device.
- (3) Value shown refers to DC input reference voltage, V_{REF(DC)}.
- (4) Value shown refers to AC input reference voltage, V_{REF(AC)}.

Table 1-17. Single-Ended SSTL and HSTL I/O Standards Signal Specifications for Cyclone IV Devices

I/O Standard	V _{IL(DC)} (V)		V _{IH(DC)} (V)		V _{IL(AC)} (V)		V _{IH(AC)} (V)		V _{OL} (V)	V _{OH} (V)	I _{OL} (mA)	I _{OH} (mA)
	Min	Max	Min	Max	Min	Max	Min	Max	Max	Min		
SSTL-2 Class I	—	V _{REF} - 0.18	V _{REF} + 0.18	—	—	V _{REF} - 0.35	V _{REF} + 0.35	—	V _{TT} - 0.57	V _{TT} + 0.57	8.1	-8.1
SSTL-2 Class II	—	V _{REF} - 0.18	V _{REF} + 0.18	—	—	V _{REF} - 0.35	V _{REF} + 0.35	—	V _{TT} - 0.76	V _{TT} + 0.76	16.4	-16.4
SSTL-18 Class I	—	V _{REF} - 0.125	V _{REF} + 0.125	—	—	V _{REF} - 0.25	V _{REF} + 0.25	—	V _{TT} - 0.475	V _{TT} + 0.475	6.7	-6.7
SSTL-18 Class II	—	V _{REF} - 0.125	V _{REF} + 0.125	—	—	V _{REF} - 0.25	V _{REF} + 0.25	—	0.28	V _{CCIO} - 0.28	13.4	-13.4
HSTL-18 Class I	—	V _{REF} - 0.1	V _{REF} + 0.1	—	—	V _{REF} - 0.2	V _{REF} + 0.2	—	0.4	V _{CCIO} - 0.4	8	-8
HSTL-18 Class II	—	V _{REF} - 0.1	V _{REF} + 0.1	—	—	V _{REF} - 0.2	V _{REF} + 0.2	—	0.4	V _{CCIO} - 0.4	16	-16
HSTL-15 Class I	—	V _{REF} - 0.1	V _{REF} + 0.1	—	—	V _{REF} - 0.2	V _{REF} + 0.2	—	0.4	V _{CCIO} - 0.4	8	-8
HSTL-15 Class II	—	V _{REF} - 0.1	V _{REF} + 0.1	—	—	V _{REF} - 0.2	V _{REF} + 0.2	—	0.4	V _{CCIO} - 0.4	16	-16
HSTL-12 Class I	-0.15	V _{REF} - 0.08	V _{REF} + 0.08	V _{CCIO} + 0.15	-0.24	V _{REF} - 0.15	V _{REF} + 0.15	V _{CCIO} + 0.24	0.25 × V _{CCIO}	0.75 × V _{CCIO}	8	-8
HSTL-12 Class II	-0.15	V _{REF} - 0.08	V _{REF} + 0.08	V _{CCIO} + 0.15	-0.24	V _{REF} - 0.15	V _{REF} + 0.15	V _{CCIO} + 0.24	0.25 × V _{CCIO}	0.75 × V _{CCIO}	14	-14

Power Consumption

Use the following methods to estimate power for a design:

- the Excel-based EPE
- the Quartus® II PowerPlay power analyzer feature

The interactive Excel-based EPE is used prior to designing the device to get a magnitude estimate of the device power. The Quartus II PowerPlay power analyzer provides better quality estimates based on the specifics of the design after place-and-route is complete. The PowerPlay power analyzer can apply a combination of user-entered, simulation-derived, and estimated signal activities that, combined with detailed circuit models, can yield very accurate power estimates.



For more information about power estimation tools, refer to the *Early Power Estimator User Guide* and the *PowerPlay Power Analysis* chapter in volume 3 of the *Quartus II Handbook*.

Switching Characteristics

This section provides performance characteristics of Cyclone IV core and periphery blocks for commercial grade devices.

These characteristics can be designated as Preliminary or Final.

- Preliminary characteristics are created using simulation results, process data, and other known parameters. The upper-right hand corner of these tables show the designation as “Preliminary”.
- Final numbers are based on actual silicon characterization and testing. The numbers reflect the actual performance of the device under worst-case silicon process, voltage, and junction temperature conditions. There are no designations on finalized tables.

Table 1-21. Transceiver Specification for Cyclone IV GX Devices (Part 2 of 4)

Symbol/ Description	Conditions	C6			C7, I7			C8			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Receiver											
Supported I/O Standards	1.4 V PCML, 1.5 V PCML, 2.5 V PCML, LVPECL, LVDS										
Data rate (F324 and smaller package) ⁽¹⁵⁾	—	600	—	2500	600	—	2500	600	—	2500	Mbps
Data rate (F484 and larger package) ⁽¹⁵⁾	—	600	—	3125	600	—	3125	600	—	2500	Mbps
Absolute V _{MAX} for a receiver pin ⁽³⁾	—	—	—	1.6	—	—	1.6	—	—	1.6	V
Operational V _{MAX} for a receiver pin	—	—	—	1.5	—	—	1.5	—	—	1.5	V
Absolute V _{MIN} for a receiver pin	—	−0.4	—	—	−0.4	—	—	−0.4	—	—	V
Peak-to-peak differential input voltage V _{ID} (diff p-p)	V _{ICM} = 0.82 V setting, Data Rate = 600 Mbps to 3.125 Gbps	0.1	—	2.7	0.1	—	2.7	0.1	—	2.7	V
V _{ICM}	V _{ICM} = 0.82 V setting	—	820 ± 10%	—	—	820 ± 10%	—	—	820 ± 10%	—	mV
Differential on-chip termination resistors	100−Ω setting	—	100	—	—	100	—	—	100	—	Ω
	150−Ω setting	—	150	—	—	150	—	—	150	—	Ω
Differential and common mode return loss	PIPE, Serial Rapid I/O SR, SATA, CPRI LV, SDI, XAUI	Compliant									—
Programmable ppm detector ⁽⁴⁾	—	± 62.5, 100, 125, 200, 250, 300									ppm
Clock data recovery (CDR) ppm tolerance (without spread-spectrum clocking enabled)	—	—	—	±300 ⁽⁵⁾ , ±350 ^{(6), (7)}	—	—	±300 ⁽⁵⁾ , ±350 ^{(6), (7)}	—	—	±300 ⁽⁵⁾ , ±350 ^{(6), (7)}	ppm
CDR ppm tolerance (with synchronous spread-spectrum clocking enabled) ⁽⁸⁾	—	—	—	350 to −5350 ^{(7), (9)}	—	—	350 to −5350 ^{(7), (9)}	—	—	350 to −5350 ^{(7), (9)}	ppm
Run length	—	—	80	—	—	80	—	—	80	—	UI
Programmable equalization	No Equalization	—	—	1.5	—	—	1.5	—	—	1.5	dB
	Medium Low	—	—	4.5	—	—	4.5	—	—	4.5	dB
	Medium High	—	—	5.5	—	—	5.5	—	—	5.5	dB
	High	—	—	7	—	—	7	—	—	7	dB

Table 1–21. Transceiver Specification for Cyclone IV GX Devices (Part 4 of 4)

Symbol/ Description	Conditions	C6			C7, I7			C8			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
PLD-Transceiver Interface											
Interface speed (F324 and smaller package)	—	25	—	125	25	—	125	25	—	125	MHz
Interface speed (F484 and larger package)	—	25	—	156.25	25	—	156.25	25	—	156.25	MHz
Digital reset pulse width	—	Minimum is 2 parallel clock cycles									

Notes to Table 1–21:

- (1) This specification is valid for transmitter output jitter specification with a maximum total jitter value of 112 ps, typically for 3.125 Gbps SRIO and XAUI protocols.
- (2) The minimum `reconfig_clk` frequency is 2.5 MHz if the transceiver channel is configured in **Transmitter Only** mode. The minimum `reconfig_clk` frequency is 37.5 MHz if the transceiver channel is configured in **Receiver Only** or **Receiver and Transmitter** mode.
- (3) The device cannot tolerate prolonged operation at this absolute maximum.
- (4) The rate matcher supports only up to ± 300 parts per million (ppm).
- (5) Supported for the F169 and F324 device packages only.
- (6) Supported for the F484, F672, and F896 device packages only. Pending device characterization.
- (7) To support CDR ppm tolerance greater than ± 300 ppm, implement ppm detector in user logic and configure CDR to Manual Lock Mode.
- (8) Asynchronous spread-spectrum clocking is not supported.
- (9) For the EP4CGX30 (F484 package only), EP4CGX50, and EP4CGX75 devices, the CDR ppl tolerance is ± 200 ppm.
- (10) Time taken until `p11_locked` goes high after `p11_powerdown` deasserts.
- (11) Time that the CDR must be kept in lock-to-reference mode after `rx_analogreset` deasserts and before `rx_locktodata` is asserted in manual mode.
- (12) Time taken to recover valid data after the `rx_locktodata` signal is asserted in manual mode (Figure 1–2), or after `rx_freqlocked` signal goes high in automatic mode (Figure 1–3).
- (13) Time taken to recover valid data after the `rx_locktodata` signal is asserted in manual mode.
- (14) Time taken to recover valid data after the `rx_freqlocked` signal goes high in automatic mode.
- (15) To support data rates lower than the minimum specification through oversampling, use the CDR in LTR mode only.

Figure 1-4 shows the differential receiver input waveform.

Figure 1-4. Receiver Input Waveform

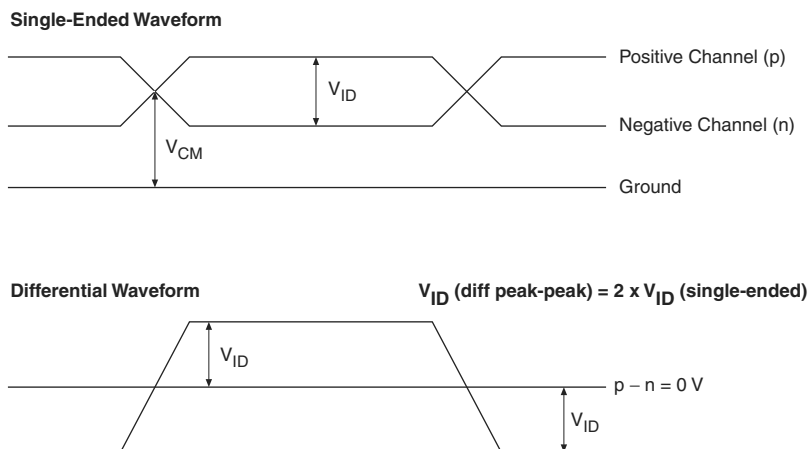


Figure 1-5 shows the transmitter output waveform.

Figure 1-5. Transmitter Output Waveform

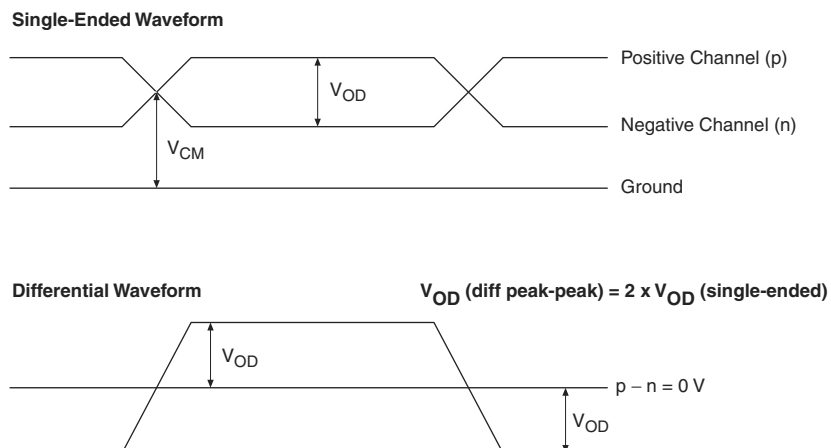


Table 1-22 lists the typical V_{OD} for Tx term that equals 100 Ω .

Table 1-22. Typical V_{OD} Setting, Tx Term = 100 Ω

Symbol	V_{OD} Setting (mV)					
	1	2	3	4 (1)	5	6
V_{OD} differential peak to peak typical (mV)	400	600	800	900	1000	1200

Note to Table 1-22:

(1) This setting is required for compliance with the PCIe protocol.

Embedded Multiplier Specifications

Table 1–26 lists the embedded multiplier specifications for Cyclone IV devices.

Table 1–26. Embedded Multiplier Specifications for Cyclone IV Devices

Mode	Resources Used	Performance					Unit
	Number of Multipliers	C6	C7, I7, A7	C8	C8L, I8L	C9L	
9 × 9-bit multiplier	1	340	300	260	240	175	MHz
18 × 18-bit multiplier	1	287	250	200	185	135	MHz

Memory Block Specifications

Table 1–27 lists the M9K memory block specifications for Cyclone IV devices.

Table 1–27. Memory Block Performance Specifications for Cyclone IV Devices

Memory	Mode	Resources Used		Performance					Unit
		LEs	M9K Memory	C6	C7, I7, A7	C8	C8L, I8L	C9L	
M9K Block	FIFO 256 × 36	47	1	315	274	238	200	157	MHz
	Single-port 256 × 36	0	1	315	274	238	200	157	MHz
	Simple dual-port 256 × 36 CLK	0	1	315	274	238	200	157	MHz
	True dual port 512 × 18 single CLK	0	1	315	274	238	200	157	MHz

Configuration and JTAG Specifications

Table 1–28 lists the configuration mode specifications for Cyclone IV devices.

Table 1–28. Passive Configuration Mode Specifications for Cyclone IV Devices ⁽¹⁾

Programming Mode	V _{CCINT} Voltage Level (V)	DCLK f _{MAX}	Unit
Passive Serial (PS)	1.0 ⁽³⁾	66	MHz
	1.2	133	MHz
Fast Passive Parallel (FPP) ⁽²⁾	1.0 ⁽³⁾	66	MHz
	1.2 ⁽⁴⁾	100	MHz

Notes to Table 1–28:

- (1) For more information about PS and FPP configuration timing parameters, refer to the *Configuration and Remote System Upgrades in Cyclone IV Devices* chapter.
- (2) FPP configuration mode supports all Cyclone IV E devices (except for E144 package devices) and EP4CGX50, EP4CGX75, EP4CGX110, and EP4CGX150 only.
- (3) V_{CCINT} = 1.0 V is only supported for Cyclone IV E 1.0 V core voltage devices.
- (4) Cyclone IV E devices support 1.2 V V_{CCINT}. Cyclone IV E 1.2 V core voltage devices support 133 MHz DCLK f_{MAX} for EP4CE6, EP4CE10, EP4CE15, EP4CE22, EP4CE30, and EP4CE40 only.

Table 1–32. Emulated RSDS_E_1R Transmitter Timing Specifications for Cyclone IV Devices ^{(1), (3)} (Part 2 of 2)

Symbol	Modes	C6			C7, I7			C8, A7			C8L, I8L			C9L			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
t_{LOCK} ⁽²⁾	—	—	—	1	—	—	1	—	—	1	—	—	1	—	—	1	ms

Notes to Table 1–32:

- (1) Emulated RSDS_E_1R transmitter is supported at the output pin of all I/O Banks of Cyclone IV E devices and I/O Banks 3, 4, 5, 6, 7, 8, and 9 of Cyclone IV GX devices.
- (2) t_{LOCK} is the time required for the PLL to lock from the end-of-device configuration.
- (3) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades. Cyclone IV GX devices only support C6, C7, C8, and I7 speed grades.

Table 1–33. Mini-LVDS Transmitter Timing Specifications for Cyclone IV Devices ^{(1), (2), (4)}

Symbol	Modes	C6			C7, I7			C8, A7			C8L, I8L			C9L			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f_{HSCLK} (input clock frequency)	×10	5	—	200	5	—	155.5	5	—	155.5	5	—	155.5	5	—	132.5	MHz
	×8	5	—	200	5	—	155.5	5	—	155.5	5	—	155.5	5	—	132.5	MHz
	×7	5	—	200	5	—	155.5	5	—	155.5	5	—	155.5	5	—	132.5	MHz
	×4	5	—	200	5	—	155.5	5	—	155.5	5	—	155.5	5	—	132.5	MHz
	×2	5	—	200	5	—	155.5	5	—	155.5	5	—	155.5	5	—	132.5	MHz
	×1	5	—	400	5	—	311	5	—	311	5	—	311	5	—	265	MHz
Device operation in Mbps	×10	100	—	400	100	—	311	100	—	311	100	—	311	100	—	265	Mbps
	×8	80	—	400	80	—	311	80	—	311	80	—	311	80	—	265	Mbps
	×7	70	—	400	70	—	311	70	—	311	70	—	311	70	—	265	Mbps
	×4	40	—	400	40	—	311	40	—	311	40	—	311	40	—	265	Mbps
	×2	20	—	400	20	—	311	20	—	311	20	—	311	20	—	265	Mbps
	×1	10	—	400	10	—	311	10	—	311	10	—	311	10	—	265	Mbps
t_{DUTY}	—	45	—	55	45	—	55	45	—	55	45	—	55	45	—	55	%
TCCS	—	—	—	200	—	—	200	—	—	200	—	—	200	—	—	200	ps
Output jitter (peak to peak)	—	—	—	500	—	—	500	—	—	550	—	—	600	—	—	700	ps
t_{RISE}	20 – 80%, $C_{\text{LOAD}} = 5 \text{ pF}$	—	500	—	—	500	—	—	500	—	—	500	—	—	500	—	ps
t_{FALL}	20 – 80%, $C_{\text{LOAD}} = 5 \text{ pF}$	—	500	—	—	500	—	—	500	—	—	500	—	—	500	—	ps
t_{LOCK} ⁽³⁾	—	—	—	1	—	—	1	—	—	1	—	—	1	—	—	1	ms

Notes to Table 1–33:

- (1) Applicable for true and emulated mini-LVDS transmitter.
- (2) Cyclone IV E—true mini-LVDS transmitter is only supported at the output pin of Row I/O Banks 1, 2, 5, and 6. Emulated mini-LVDS transmitter is supported at the output pin of all I/O banks.
Cyclone IV GX—true mini-LVDS transmitter is only supported at the output pin of Row I/O Banks 5 and 6. Emulated mini-LVDS transmitter is supported at the output pin of I/O Banks 3, 4, 5, 6, 7, 8, and 9.
- (3) t_{LOCK} is the time required for the PLL to lock from the end-of-device configuration.
- (4) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades. Cyclone IV GX devices only support C6, C7, C8, and I7 speed grades.

IOE Programmable Delay

Table 1–40 and Table 1–41 list the IOE programmable delay for Cyclone IV E 1.0 V core voltage devices.

Table 1–40. IOE Programmable Delay on Column Pins for Cyclone IV E 1.0 V Core Voltage Devices ^{(1), (2)}

Parameter	Paths Affected	Number of Setting	Min Offset	Max Offset					Unit
				Fast Corner		Slow Corner			
				C8L	I8L	C8L	C9L	I8L	
Input delay from pin to internal cells	Pad to I/O dataout to core	7	0	2.054	1.924	3.387	4.017	3.411	ns
Input delay from pin to input register	Pad to I/O input register	8	0	2.010	1.875	3.341	4.252	3.367	ns
Delay from output register to output pin	I/O output register to pad	2	0	0.641	0.631	1.111	1.377	1.124	ns
Input delay from dual-purpose clock pin to fan-out destinations	Pad to global clock network	12	0	0.971	0.931	1.684	2.298	1.684	ns

Notes to Table 1–40:

- (1) The incremental values for the settings are generally linear. For the exact values for each setting, use the latest version of the Quartus II software.
- (2) The minimum and maximum offset timing numbers are in reference to setting **0** as available in the Quartus II software.

Table 1–41. IOE Programmable Delay on Row Pins for Cyclone IV E 1.0 V Core Voltage Devices ^{(1), (2)}

Parameter	Paths Affected	Number of Setting	Min Offset	Max Offset					Unit
				Fast Corner		Slow Corner			
				C8L	I8L	C8L	C9L	I8L	
Input delay from pin to internal cells	Pad to I/O dataout to core	7	0	2.057	1.921	3.389	4.146	3.412	ns
Input delay from pin to input register	Pad to I/O input register	8	0	2.059	1.919	3.420	4.374	3.441	ns
Delay from output register to output pin	I/O output register to pad	2	0	0.670	0.623	1.160	1.420	1.168	ns
Input delay from dual-purpose clock pin to fan-out destinations	Pad to global clock network	12	0	0.960	0.919	1.656	2.258	1.656	ns

Notes to Table 1–41:

- (1) The incremental values for the settings are generally linear. For the exact values for each setting, use the latest version of the Quartus II software.
- (2) The minimum and maximum offset timing numbers are in reference to setting **0** as available in the Quartus II software.

Table 1–42 and Table 1–43 list the IOE programmable delay for Cyclone IV E 1.2 V core voltage devices.

Table 1–42. IOE Programmable Delay on Column Pins for Cyclone IV E 1.2 V Core Voltage Devices ^{(1), (2)}

Parameter	Paths Affected	Number of Setting	Min Offset	Max Offset								Unit
				Fast Corner			Slow Corner					
				C6	I7	A7	C6	C7	C8	I7	A7	
Input delay from pin to internal cells	Pad to I/O dataout to core	7	0	1.314	1.211	1.211	2.177	2.340	2.433	2.388	2.508	ns
Input delay from pin to input register	Pad to I/O input register	8	0	1.307	1.203	1.203	2.19	2.387	2.540	2.430	2.545	ns
Delay from output register to output pin	I/O output register to pad	2	0	0.437	0.402	0.402	0.747	0.820	0.880	0.834	0.873	ns
Input delay from dual-purpose clock pin to fan-out destinations	Pad to global clock network	12	0	0.693	0.665	0.665	1.200	1.379	1.532	1.393	1.441	ns

Notes to Table 1–42:

- (1) The incremental values for the settings are generally linear. For the exact values for each setting, use the latest version of the Quartus II software.
- (2) The minimum and maximum offset timing numbers are in reference to setting **0** as available in the Quartus II software.

Table 1–43. IOE Programmable Delay on Row Pins for Cyclone IV E 1.2 V Core Voltage Devices ^{(1), (2)}

Parameter	Paths Affected	Number of Setting	Min Offset	Max Offset								Unit
				Fast Corner			Slow Corner					
				C6	I7	A7	C6	C7	C8	I7	A7	
Input delay from pin to internal cells	Pad to I/O dataout to core	7	0	1.314	1.209	1.209	2.201	2.386	2.510	2.429	2.548	ns
Input delay from pin to input register	Pad to I/O input register	8	0	1.312	1.207	1.207	2.202	2.402	2.558	2.447	2.557	ns
Delay from output register to output pin	I/O output register to pad	2	0	0.458	0.419	0.419	0.783	0.861	0.924	0.875	0.915	ns
Input delay from dual-purpose clock pin to fan-out destinations	Pad to global clock network	12	0	0.686	0.657	0.657	1.185	1.360	1.506	1.376	1.422	ns

Notes to Table 1–43:

- (1) The incremental values for the settings are generally linear. For the exact values for each setting, use the latest version of the Quartus II software.
- (2) The minimum and maximum offset timing numbers are in reference to setting **0** as available in the Quartus II software.

Table 1-46. Glossary (Part 4 of 5)

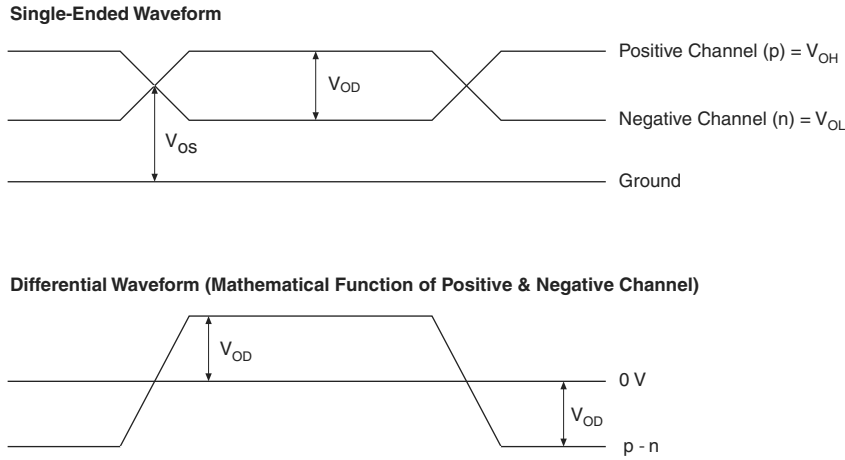
Letter	Term	Definitions
T	t_C	High-speed receiver and transmitter input and output clock period.
	Channel-to-channel-skew (TCCS)	High-speed I/O block: The timing difference between the fastest and slowest output edges, including t_{CO} variation and clock skew. The clock is included in the TCCS measurement.
	t_{cin}	Delay from the clock pad to the I/O input register.
	t_{CO}	Delay from the clock pad to the I/O output.
	t_{cout}	Delay from the clock pad to the I/O output register.
	t_{DUTY}	High-speed I/O block: Duty cycle on high-speed transmitter output clock.
	t_{FALL}	Signal high-to-low transition time (80–20%).
	t_H	Input register hold time.
	Timing Unit Interval (TUI)	High-speed I/O block: The timing budget allowed for skew, propagation delays, and data sampling window. (TUI = $1/(\text{Receiver Input Clock Frequency Multiplication Factor}) = t_C/w$).
	$t_{INJITTER}$	Period jitter on the PLL clock input.
	$t_{OUTJITTER_DEDCLK}$	Period jitter on the dedicated clock output driven by a PLL.
	$t_{OUTJITTER_IO}$	Period jitter on the general purpose I/O driven by a PLL.
	t_{pllcin}	Delay from the PLL inclk pad to the I/O input register.
	$t_{pllcout}$	Delay from the PLL inclk pad to the I/O output register.
	Transmitter Output Waveform	<p>Transmitter output waveforms for the LVDS, mini-LVDS, PPDS and RSDS Differential I/O Standards:</p> 
	t_{RISE}	Signal low-to-high transition time (20–80%).
	t_{SU}	Input register setup time.
U	—	—

Table 1-46. Glossary (Part 5 of 5)

Letter	Term	Definitions
V	$V_{CM(DC)}$	DC common mode input voltage.
	$V_{DIF(AC)}$	AC differential input voltage: The minimum AC input differential voltage required for switching.
	$V_{DIF(DC)}$	DC differential input voltage: The minimum DC input differential voltage required for switching.
	V_{ICM}	Input common mode voltage: The common mode of the differential signal at the receiver.
	V_{ID}	Input differential voltage swing: The difference in voltage between the positive and complementary conductors of a differential transmission at the receiver.
	V_{IH}	Voltage input high: The minimum positive voltage applied to the input that is accepted by the device as a logic high.
	$V_{IH(AC)}$	High-level AC input voltage.
	$V_{IH(DC)}$	High-level DC input voltage.
	V_{IL}	Voltage input low: The maximum positive voltage applied to the input that is accepted by the device as a logic low.
	$V_{IL(AC)}$	Low-level AC input voltage.
	$V_{IL(DC)}$	Low-level DC input voltage.
	V_{IN}	DC input voltage.
	V_{OCM}	Output common mode voltage: The common mode of the differential signal at the transmitter.
	V_{OD}	Output differential voltage swing: The difference in voltage between the positive and complementary conductors of a differential transmission at the transmitter. $V_{OD} = V_{OH} - V_{OL}$.
	V_{OH}	Voltage output high: The maximum positive voltage from an output that the device considers is accepted as the minimum positive high level.
	V_{OL}	Voltage output low: The maximum positive voltage from an output that the device considers is accepted as the maximum positive low level.
	V_{OS}	Output offset voltage: $V_{OS} = (V_{OH} + V_{OL}) / 2$.
	$V_{OX(AC)}$	AC differential output cross point voltage: the voltage at which the differential output signals must cross.
	V_{REF}	Reference voltage for the SSTL and HSTL I/O standards.
	$V_{REF(AC)}$	AC input reference voltage for the SSTL and HSTL I/O standards. $V_{REF(AC)} = V_{REF(DC)} + \text{noise}$. The peak-to-peak AC noise on V_{REF} must not exceed 2% of $V_{REF(DC)}$.
	$V_{REF(DC)}$	DC input reference voltage for the SSTL and HSTL I/O standards.
	$V_{SWING(AC)}$	AC differential input voltage: AC input differential voltage required for switching. For the SSTL differential I/O standard, refer to Input Waveforms.
	$V_{SWING(DC)}$	DC differential input voltage: DC input differential voltage required for switching. For the SSTL differential I/O standard, refer to Input Waveforms.
	V_{TT}	Termination voltage for the SSTL and HSTL I/O standards.
	$V_X(AC)$	AC differential input cross point voltage: The voltage at which the differential input signals must cross.
W	—	—
X	—	—
Y	—	—
Z	—	—

Document Revision History

Table 1-47 lists the revision history for this chapter.

Table 1-47. Document Revision History

Date	Version	Changes
March 2016	2.0	Updated note (5) in Table 1-21 to remove support for the N148 package.
October 2014	1.9	Updated maximum value for V_{CCD_PLL} in Table 1-1. Removed extended temperature note in Table 1-3.
December 2013	1.8	Updated Table 1-21 by adding Note (15).
May 2013	1.7	Updated Table 1-15 by adding Note (4).
October 2012	1.6	<ul style="list-style-type: none"> ■ Updated the maximum value for V_I, V_{CCD_PLL}, V_{CCIO}, V_{CC_CLKIN}, V_{CCH_GXB}, and V_{CCA_GXB} in Table 1-1. ■ Updated Table 1-11 and Table 1-22. ■ Updated Table 1-21 to include peak-to-peak differential input voltage for the Cyclone IV GX transceiver input reference clock. ■ Updated Table 1-29 to include the typical $DCLK$ value. ■ Updated the minimum f_{HCLK} value in Table 1-31, Table 1-32, Table 1-33, Table 1-34, and Table 1-35.
November 2011	1.5	<ul style="list-style-type: none"> ■ Updated “Maximum Allowed Overshoot or Undershoot Voltage”, “Operating Conditions”, and “PLL Specifications” sections. ■ Updated Table 1-2, Table 1-3, Table 1-4, Table 1-5, Table 1-8, Table 1-9, Table 1-15, Table 1-18, Table 1-19, and Table 1-21. ■ Updated Figure 1-1.
December 2010	1.4	<ul style="list-style-type: none"> ■ Updated for the Quartus II software version 10.1 release. ■ Updated Table 1-21 and Table 1-25. ■ Minor text edits.
July 2010	1.3	<p>Updated for the Quartus II software version 10.0 release:</p> <ul style="list-style-type: none"> ■ Updated Table 1-3, Table 1-4, Table 1-21, Table 1-25, Table 1-28, Table 1-30, Table 1-40, Table 1-41, Table 1-42, Table 1-43, Table 1-44, and Table 1-45. ■ Updated Figure 1-2 and Figure 1-3. ■ Removed SW Requirement and TCCS for Cyclone IV Devices tables. ■ Minor text edits.
March 2010	1.2	<p>Updated to include automotive devices:</p> <ul style="list-style-type: none"> ■ Updated the “Operating Conditions” and “PLL Specifications” sections. ■ Updated Table 1-1, Table 1-8, Table 1-9, Table 1-21, Table 1-26, Table 1-27, Table 1-31, Table 1-32, Table 1-33, Table 1-34, Table 1-35, Table 1-36, Table 1-37, Table 1-38, Table 1-40, Table 1-42, and Table 1-43. ■ Added Table 1-5 to include ESD for Cyclone IV devices GPIOs and HSSI I/Os. ■ Added Table 1-44 and Table 1-45 to include IOE programmable delay for Cyclone IV E 1.2 V core voltage devices. ■ Minor text edits.

Table 1–47. Document Revision History

Date	Version	Changes
February 2010	1.1	<ul style="list-style-type: none">■ Updated Table 1–3 through Table 1–44 to include information for Cyclone IV E devices and Cyclone IV GX devices for Quartus II software version 9.1 SP1 release.■ Minor text edits.
November 2009	1.0	Initial release.

